


<b>Search Notes</b>  	<b>Application/Control No.</b>  10775824	<b>Applicant(s)/Patent Under Reexamination</b>  LEUNG ET AL.
	<b>Examiner</b>  Le Nguyen	<b>Art Unit</b>  2174

SEARCHED			
Class	Subclass	Date	Examiner
715	763	11/19/07	lvn

SEARCH NOTES		
Search Notes	Date	Examiner
ACM library, IEEE Xplore. EPO, JPO.	11/19/07	lvn
US-PGPub, USPAT: 715/539,502,964,712,854,853,734,850,854,764,765,836,839,762,763,846,849,835	11/19/07	lvn
confirmed maintaining Harrington rejection to amended language of independent claim w/Ba Huynhs	11/21/07	lvn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	763	11/19/07	lvn